

Supporting Information

Tuning Crystal Polymorphs of a π -Extended Tetrathiafulvalene-based Cruciform Molecule towards High-Performance Organic Field-Effect Transistors

Linlin Feng,^{a,b} Huanli Dong,^{b,*} Qingyuan Li,^{a,b} Weigang Zhu,^b Gege Qiu,^{a,b} Shang Ding,^{a,b} Yang Li,^b Mikkel A. Christensen,^c Christian R. Parker,^c Zhongming Wei,^d Mogens Brøndsted Nielsen,^c Wenping Hu^{b,e}

^aBeijing Key Laboratory for Optical Materials and Photonic Devices, Department of Chemistry, Capital Normal University, Beijing 100048, China.

^bBeijing National Laboratory for Molecular Sciences, Key Laboratory of Organic Solids, Institute of Chemistry, Chinese Academy of Sciences, Beijing 100190, China.

^cDepartment of Chemistry, University of Copenhagen, Universitetsparken 5, DK-2100, Copenhagen Ø, Denmark.

^dState Key Laboratory of Superlattices and Microstructures, Institute of Semiconductors, Chinese Academy of Sciences, Beijing 100083, China.

^eTianjin Key Laboratory of Molecular Optoelectronic Sciences, Department of Chemistry, School of Sciences, Tianjin University, & Collaborative Innovation Center of Chemical Science and Engineering (Tianjin), Tianjin 300072, China.

Section 1. Detailed Experimental Conditions

Cleaning of substrates. First the Si/SiO₂ substrates were cleaned with piranha solution (H₂O₂/H₂SO₄ = 1:2) for 10 min and then washed with deionized water and then isopropyl alcohol to remove the residual solvent or water. Subsequently the substrates were dried with high-purity nitrogen gas and cleaned with oxygen plasma (about 5 min). Finally the clean wafers were put in vacuum oven at 90 °C for 1 h and then modified with OTS at 120 °C for 2 h. The modified substrates were cleaned with hexane, chloroform and isopropyl alcohol successively for use in following.

Single crystal preparation. For both IF-TTF solutions, 25 μL solutions were dropped on 1×1 cm² OTS-modified Si/SiO₂ substrates which were put in weighing bottles. Single crystals were obtained after the solvent evaporation at the room temperature overnight. Then the crystals were annealed in vacuum at 80°C for α-phase single crystal and 120°C for β-phase before the fabrication of the devices.

Device fabrication. Top-contact bottom-gate devices single crystal transistors were fabricated through an Au-layer stamping technique^[1]. Organic field-effect transistor characteristics were carried out at room temperature in air on a Keithley 4200 SCS and Micromanipulator 6150 probe station and the mobility was extracted from the saturation region by using the equation of $I_{DS}=(W/2L)C\mu(V_G-V_T)^2$.

Characterizations. The microscope images of the single crystals were acquired by an Olympus BX51 optical microscope (Vision Engineering Co., UK). The structures were analyzed by XRD (Rigaku D/max 2500) and SAED patterns (TECNAI T20 electron microscope (FEI, USA)). Single crystal data were obtained using a Single crystal X- ray diffraction (Rigaku ST Saturn 724+).

Section 2. Supporting data

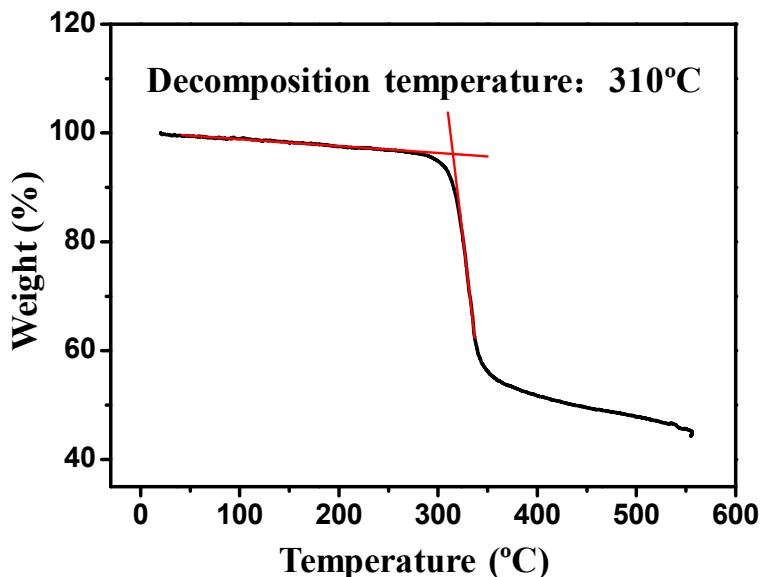


Figure S1. TGA of IF-TTF.

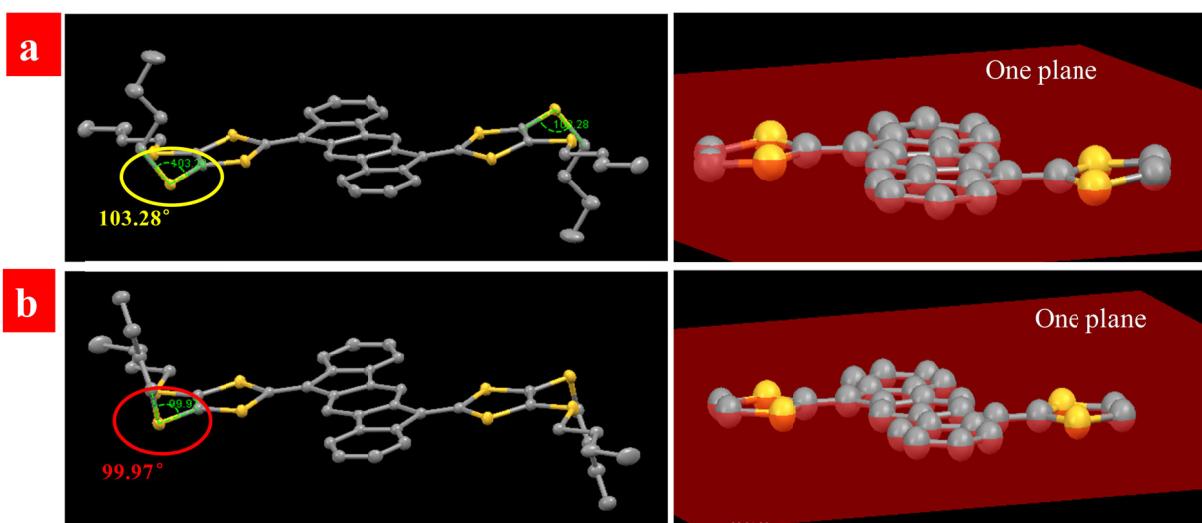


Figure S2. The different intersection angles between the molecular conjugated plane of IF and TTF units (right) and the SBu substituent groups that out of the planes for α -phase (a) and β -phase (b) crystals.

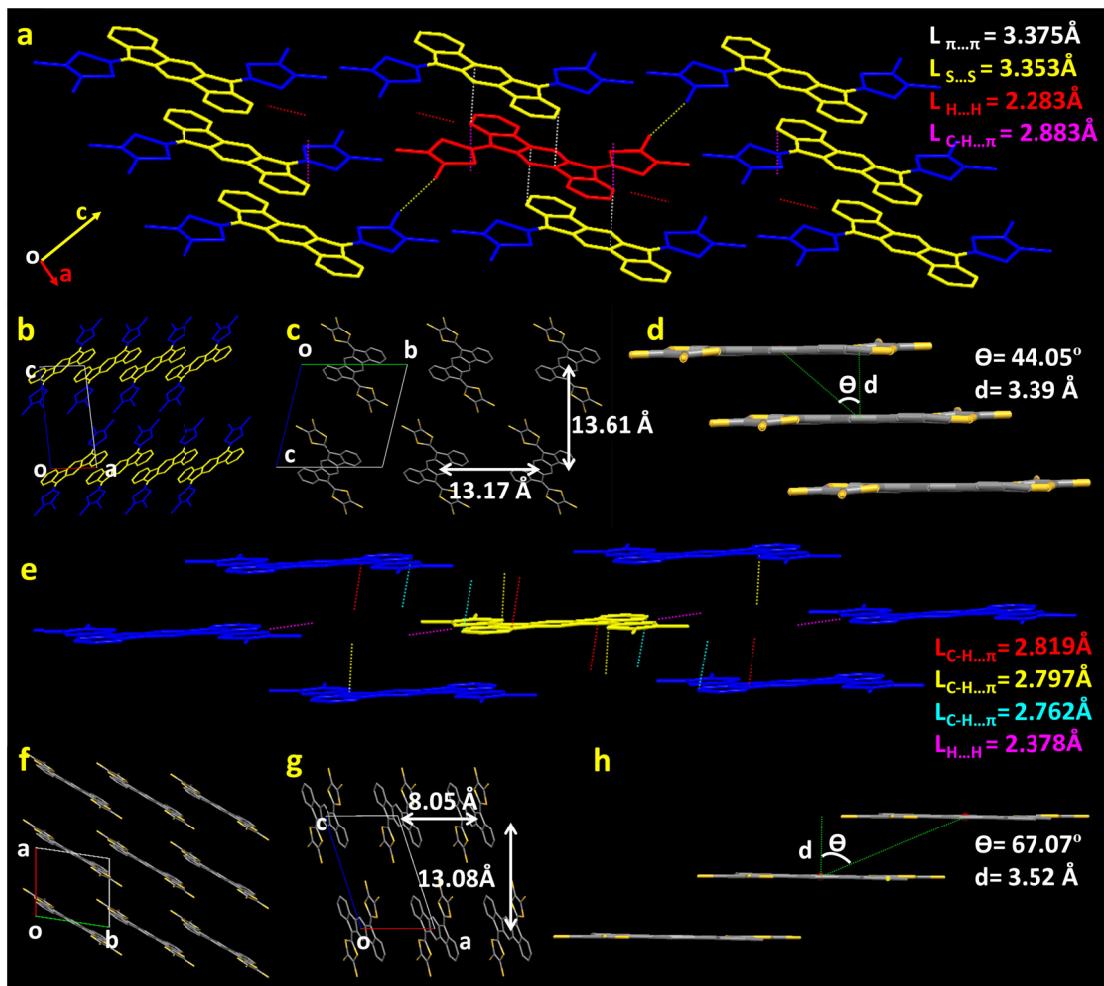


Figure S3. (a) View interactions of α -phase crystal polymorph: one molecular with eight neighbors. View of the molecular packing structure along the b -axis (b) and the layered structure along the cell a -axis (c). (d) Stacking diagram showing $\pi \dots \pi$ interaction in α -phase crystal polymorph. (e) View interactions of β -phase crystal polymorph: one molecular with six neighbors. View of the molecular packing structure along the c -axis (f) and the layered structure along the cell b -axis (g). (h) Stacking diagram showing $\pi \dots \pi$ interaction in platelet-shaped crystal polymorph (all the alkyl chains have been omitted for clarity).

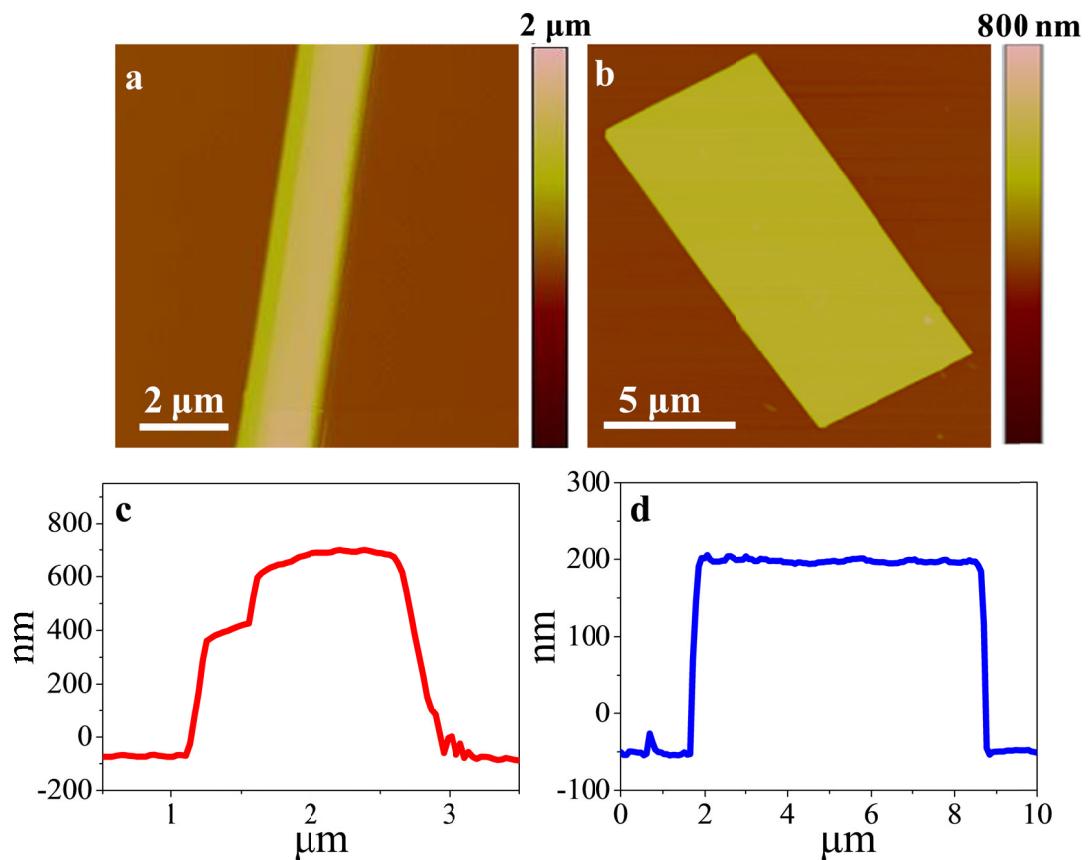


Figure S4. AFM images and height curves of α -phase (a,c) and β -phase (b,d) IF-TTF single crystals.

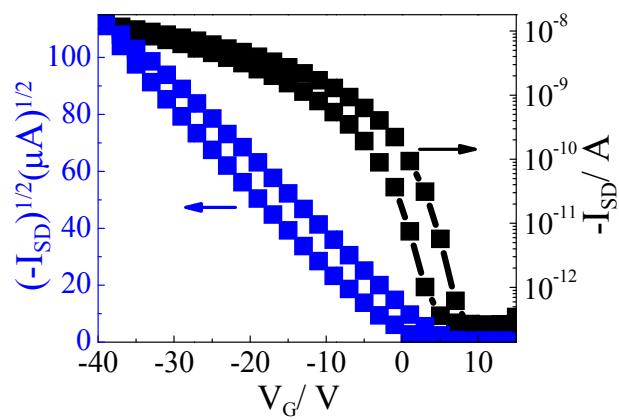


Figure S5. The hysteresis transfer curves of IF-TTF crystal-based transistors.

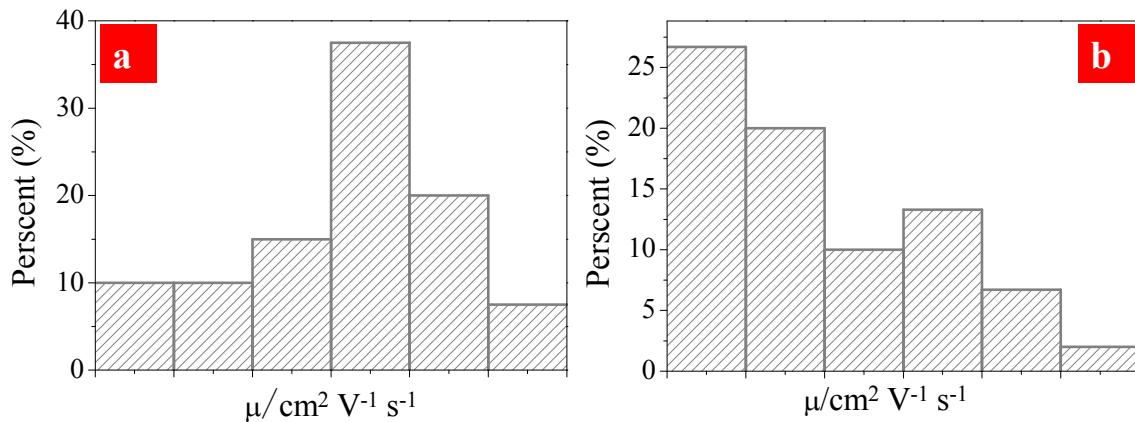


Figure S6. The bar charts of the frequency distributions of the 40 devices for α -phase a) and β -phase b) IF-TTF crystals

Table S1 The comparison of detailed structure parameters for α -phase and β -phase IF-TTF crystals

Identification code	mx4406 (α -phase)	CCDC:962757 (β -phase)
Crystal size (mm ³)	$0.38 \times 0.06 \times 0.03$	$0.36 \times 0.26 \times 0.06$
Unit cell dimensions	$a = 5.357(4) \text{ \AA}$ $b = 13.520(10) \text{ \AA}$ $c = 14.010(10) \text{ \AA}$ $\alpha = 102.979(18)^\circ$ $\beta = 94.587(18)^\circ$ $\gamma = 90.165(13)^\circ$	$a = 8.4030(6) \text{ \AA}$ $b = 9.0350(11) \text{ \AA}$ $c = 14.0030(13) \text{ \AA}$ $\alpha = 103.453(19)^\circ$ $\beta = 106.211(12)^\circ$ $\gamma = 94.229(10)^\circ$
Space group	P-1	P-1
Crystal system	Triclinic	Triclinic
Volume (Å ³)	985.4	981.833
R-factor	7.34	3

Section 3. Crystal data and structure refinement for α -phase IF-TTF crystal

Identification code	mx4406
Empirical formula	C ₄₂ H ₄₆ S ₈
Formula weight	807.27
Temperature	173.1500 K
Wavelength	0.71073 Å
Crystal system	Triclinic
Space group	P -1
Unit cell dimensions	$a = 5.357(4)$ Å $\alpha = 102.979(18)$ ° $b = 13.520(10)$ Å $\beta = 94.587(18)$ ° $c = 14.010(10)$ Å $\gamma = 90.165(13)$ °
Volume	985.4(12) Å ³
Z	1
Density (calculated)	1.360 Mg/m ³
Absorption coefficient	0.484 mm ⁻¹
F(000)	426
Crystal size	0.38 × 0.06 × 0.03 mm ³
Theta range for data collection	1.497 to 27.541 Å
Index ranges	-6<=h<=6, -17<=k<=17, -18<=l<=17
Reflections collected	11642
Independent reflections	4474 [R(int) = 0.1306]
Completeness to theta = 26.000°	99.5 %
Absorption correction	Semi-empirical from equivalents
Max. and min. transmission	1.0000 and 0.1699
Refinement method	Full-matrix least-squares on F ²
Data / restraints / parameters	4474 / 0 / 228
Goodness-of-fit on F ²	1.110
Final R indices [I>2sigma(I)]	R1 = 0.0734, wR2 = 0.1619
R indices (all data)	R1 = 0.0923, wR2 = 0.1733
Extinction coefficient	n/a
Largest diff. peak and hole	0.443 and -0.445 e.Å ⁻³

Reference

[1] Q. Tang, L. Jiang, Y. Tong, H. Li, Y. Liu, Z. Wang, W. Hu, Y. Liu, D. Zhu, *Adv. Mater.*, 2008, **20**, 2947.